

<b>Notice of References Cited</b>	Application/Control No. 10/082,314	Applicant(s)/Patent Under Reexamination ISSHIKI, FUMIO	
	Examiner Adam R. Giesy	Art Unit 2656	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Suzuki, Tatsuya et al., Fabrication and Optical Characterization of Five-Layer Asymmetric Coupled Quantum Well (FACQW), October 9, 2001, Japanese Journal of Applied Physics, Volume 41, pp. 2701-2706.
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